L Number	Hits	Search Text	DB	Time stamp
1	2961	(705/1).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:48
3	1666	wafer adj testing	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:49
4	0	((705/1).CCLS.) and (wafer adj test$)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:48
5	6442	probe adj card	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:49
6	0	((705/1).CCLS.) and (probe adj card)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:49
7	15	automat$ adj wafer adj testing	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:52
8	0	automat$ adj wafer adj testing and network	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:51
9	76	automat$ and (wafer or probe) adj4 testing and server	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:54
10	10	(automat$ and (wafer or probe) adj4 testing and server) and @pd<20010917	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:14
11	2	("20020069114").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:03
12	2	("6223092").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:09
13	6621	design$ adj2 probe	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:14

14	2	((705/1).CCLS.) and (design$ adj2 probe)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:10
15	149	design$ adj2 probe adj2 card	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:14
16	69	(design$ adj2 probe adj2 card) and @pd<20010917	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:26
17	28732	wafer and testing	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:15
18	56	((design$ adj2 probe adj2 card) and @pd<20010917) and (wafer and testing)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:16
19	166190	server and network	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:16
20	2	(((design$ adj2 probe adj2 card) and @pd<20010917) and (wafer and testing)) and (server and network)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:24
21	14	automatic adj design adj2 integrated adj circuit	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:25
22	0	(server and network) and (automatic adj design adj2 integrated adj circuit)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:25
23	0	((705/1).CCLS.) and (automatic adj design adj2 integrated adj circuit)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:25
24	22	automatic$ adj design adj2 (integrated adj circuit or chip)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:26
25	0	(server and network) and (automatic$ adj design adj2 (integrated adj circuit or chip))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:26
26	0	((705/1).CCLS.) and (automatic$ adj design adj2 (integrated adj circuit or chip))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:26

27	15	((automatic adj design adj2 integrated adj circuit) or (automatic$ adj design adj2 (integrated adj circuit or chip))) and @pd<20010917	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:32
28	12	5824570.URPN.	USPAT	2004/07/29 14:27
29	337441	computer and automatic$	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:30
30	1378	(computer and automatic$) and ((wafer adj test$) or (design$ adj2 probe) or (design$ adj2 probe adj2 card))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:31
31	7227	((705/1).CCLS.) andn ((computer and automatic$) and ((wafer adj test$) or (design$ adj2 probe) or (design$ adj2 probe adj2 card)))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:31
32	2	((705/1).CCLS.) and ((computer and automatic$) and ((wafer adj test$) or (design$ adj2 probe) or (design$ adj2 probe adj2 card)))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:32
33	100	(server and network) and ((computer and automatic$) and ((wafer adj test$) or (design$ adj2 probe) or (design$ adj2 probe adj2 card)))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:32
34	11	((server and network) and ((computer and automatic$) and ((wafer adj test$) or (design$ adj2 probe) or (design$ adj2 probe adj2 card)))) and @pd<20010917	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:38
35	1548	(700/96,97,117).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:39
36	4542	(709/203).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:39
37	0	("03and36").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:39
38	0	("03and35").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:39
39	3	(wafer adj testing) and (((700/96,97,117).CCLS.) or ((709/203).CCLS.))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:41

40	1	(design$ adj2 probe adj2 card) and (((700/96,97,117).CCLS.) or ((709/203).CCLS.))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:41
41	2	(automat$ and (wafer or probe) adj4 testing and server) and (((700/96,97,117).CCLS.) or ((709/203).CCLS.))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 14:42
-	2	("6714828").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/07/29 13:48